



Design, Automation & Test in Europe

20-24 April, 2009 - Nice, France

The European Event for Electronic System Design & Test

Track E3 - Call for Papers on:

Model-Based Design for Embedded Systems

<http://date-conference.com/date09cfp.pdf>

The 12th **DATE conference and exhibition** is the main European event bringing together designers and design automation users, researchers and vendors, as well as specialists in the hardware and software design, test and manufacturing of electronic circuits and systems. It puts strong emphasis on ICs/SoCs, reconfigurable hardware and embedded systems, including embedded software.

TOPIC AREA FOR SUBMISSIONS



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Model-based methods for:

- component-oriented design
- testing
- system verification
- software/system integration and deployment

Domain specific modeling languages

- metamodeling

Semantic foundation for composition of domain specific tool chains

PROGRAM COMMITTEE

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SUBMISSION INSTRUCTIONS

Submissions should not exceed 6 pages in length for oral presentation papers and 4 pages in length for interactive presentation (IP) papers, and should be formatted as close as possible to the final format: A4 or letter sheets, double column, single spaced, Times or equivalent font of minimum 10pt (templates are available for your convenience). *To permit blind review, submissions should not include the author names.* Any submission not in line with the above rules will be discarded.

Submission deadline	September 7, 2008
Notification of acceptance	November 17, 2008
Final version due	December 12, 2008

Sponsored by the European Design and Automation Association, the EDA Consortium, the IEEE Computer Society. (TTTC), (CEDA), ECSI, RAS and ACM SIGDA.

